



Certificate of Analysis

IARM 35L

Low Alloy 1¼Cr ½Mo / UNS K11572

Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

Al	0.017 ± 0.001	As	0.0045 ± 0.0007	B	0.00044 ± 0.00008	C	0.119 ± 0.002
Co	0.0070 ± 0.0008	Cr	1.35 ± 0.01	Cu	0.123 ± 0.003	Mn	0.535 ± 0.008
Mo	0.607 ± 0.007	N	0.0072 ± 0.0008	Nb	0.0026 ± 0.0008	Ni	0.071 ± 0.002
P	0.007 ± 0.001	S	0.014 ± 0.001	Si	0.679 ± 0.003	Sn	0.0088 ± 0.0004
Ti	0.0015 ± 0.0006	V	0.0037 ± 0.0003	W	0.004 ± 0.002		

Indicative Values listed in ppm

Bi (<10)	Ca (<20)	Cd (<10)	Mg (<30)	O (<50)	Pb (<10)	Sb (30)
Se (<20)	Ta (<20)	Zn (<20)	Zr (<40)			

Description and Intended Use

This CRM may come in the form of a solid disc or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Interpretation of Data

1. Certified values listed reflect analysis results submitted by qualified analytical laboratories using a combination of methods and instrumentation that emulate actual methods and instrumental techniques currently utilized in the analytical community, and are reported as wt% unless otherwise noted.
2. This material was tested using both the solid disks and chips prepared from individual sections of bar. The certified values are considered representative of the overall average composition of the material.
3. Any data reported and enclosed by a parentheses () is a "best estimate" and is not certified. This data could not be quantified sufficiently for certification. It was, however, reported by enough laboratories to be considered as potentially present in the matrix of the material being examined.
4. "Provisional Certificate of Analysis" reports values that support a fully certified reference material; it also indicates that values may be in a continued process of statistical evaluation and are subject to change.
5. Chips are not certified for Oxygen analysis.



The following data and accompanying statements represent all pertinent information reported in the ILAP as it applies to the chemical characterization of this material.

	Al	As	B	Bi	C	Ca	Cd	Co	Cr	Cu	Mg	Mn	Mo	N	Nb	Ni
1	0.0137	0.003	0.0003	0.0007	0.116	0.001063	<0.0001	0.006	1.31	0.115	0.0003	0.51	0.59	0.006	0.00194	0.0671
2	0.014	0.0041	0.0004	0.001	0.1166	0.0015	<0.001	0.0062	1.32	0.1186	0.001	0.523	0.592	0.0064	0.0021	0.0676
3	0.0153	0.00445	0.000413	<0.001	0.1185	<0.0005	<0.001	0.00658	1.358	0.12	0.003	0.5281	0.60	0.007	0.0022	0.0679
4	0.0156	0.0047	0.0005	<0.001	0.12	<0.001		0.007	1.359	0.1204	<0.0005	0.529	0.602	0.007	0.0023	0.07
5	0.016	0.005	0.0005		0.12			0.007	1.3597	0.123		0.53	0.602	0.00748	0.003	0.07
6	0.0168	0.005	0.0005		0.1206			0.0071	1.36	0.1235		0.5318	0.606	0.0078	0.004	0.071
7	0.0171	0.0053						0.0073	1.3602	0.1245		0.54	0.607	0.0085		0.0714
8	0.018							0.009	1.362	0.1249		0.5409	0.6102			0.072
9	0.018								1.365	0.126		0.5417	0.6118			0.072
10	0.018								1.3689	0.126		0.542	0.6127			0.072
11	0.02									0.1277		0.5429	0.6236			0.074
12										0.13		0.5559	0.626			0.0758
13																
14																
15																
Mean	0.017	0.0045	0.00044	0.001	0.119	0.001		0.007	1.35	0.123	0.001	0.535	0.607	0.0072	0.0026	0.071
STDV.	0.002	0.0008	0.00008	0.0002	0.002	0.0003		0.0009	0.02	0.004	0.001	0.01	0.01	0.0008	0.0008	0.003
Certified	0.017	0.0045	0.00044	(<0.001)	0.119	(<0.002)	(<0.001)	0.0070	1.35	0.123	(<0.003)	0.535	0.607	0.0072	0.0026	0.071
95% C.I.	0.001	0.0007	0.00008		0.002			0.0008	0.01	0.003		0.008	0.007	0.0008	0.0008	0.002
Methods	X,O,I	X,O,I,A	O,I	I,A	O,C	O,I	I,A	X,O,I	X,O,I	X,O,I	O,I	X,O,I	X,O,I	F	X,O,I	X,O,I

	O	P	Pb	S	Sb	Se	Si	Sn	Ta	Ti	V	W	Zn	Zr
1	0.00175	0.0056	0.0005	0.013	0.00145	0.0014	0.673	0.008	<0.0005	0.0009	0.003	0.002	0.001	0.0005
2	0.0024	0.0058	<0.001	0.01331	0.0018	<0.001	0.675	0.0084	<0.001	0.001	0.0035	0.002	0.002	0.001
3	0.0042	0.00589	<0.001	0.0134	0.0019	<0.001	0.6769	0.00861	<0.001	0.001	0.0035	0.00309	<0.0005	0.00102
4	<0.005	0.006	<0.001	0.0138	0.003	<0.001	0.6788	0.0089	<0.002	0.001	0.0035	0.0044	<0.001	0.002
5		0.006		0.014	0.005		0.68	0.009		0.0017	0.0036	0.005		0.004
6		0.007		0.014			0.68	0.009		0.0021	0.00369	0.0051		<0.002
7		0.0073		0.014			0.684	0.0094		0.0026	0.004	<0.0005		
8		0.0075		0.0146			0.6844				0.004	<0.001		
9		0.0078		0.0151							0.004	<0.005		
10		0.0105		0.0186							0.0046			
11														
12														
13														
14														
15														
Mean	0.003	0.007		0.014	0.003		0.679	0.0088		0.0015	0.0037	0.004	0.002	0.002
STDV.	0.001	0.001		0.002	0.001		0.004	0.0005		0.0007	0.0004	0.001	0.0007	0.001
Certified	(<0.005)	0.007	(<0.001)	0.014	(0.003)	(<0.002)	0.679	0.0088	(<0.002)	0.0015	0.0037	0.004	(<0.002)	(<0.004)
95% C.I.		0.001		0.001			0.003	0.0004		0.0006	0.0003	0.002		
Methods	F	X,O,I	O,I,A	X,O,C	X,O,I,A	X,I,A	X,O,I	X,O,I,A	X,I	X,O,I	X,O,I	X,O,I	X,I	X,O,I

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES



Participating Laboratories

Laboratory Testing, Inc.
Anderson Laboratories, Inc.
Laboratorio Prove Materiali S. Marco srl
Massachusetts Materials Research
VHG Labs

Hatfield, PA
Greendale, WI
Schio, Italy
West Boylston, MA
Manchester, NH

Exova - Burlington
TimkenSteel Corporation
Exova - Gary
Luvak Inc.

Burlington, ON
Canton, OH
Gary, IN
Boylston, MA

Traceability

Members of the "Inter-Laboratory Analysis Program" (ILAP) validate test methods and instrument performance utilizing SRMs, CRMs, and RMs produced by recognized Certifying Bodies. The specific SRMs, CRMs, and RMs applicable to the material covered by this certificate are:

ALPHA AR1648	ALPHA AR874	IARM 241A	IARM 35I	LECO 501-504	NIST 1263	NIST 1764	NIST 363	VHG 137386RR-1
ALPHA AR657	ASTM 4011	IARM 30I	IARM 35J	LECO 501-646	NIST 132A	NIST 1765	NIST 364	VHG 80028-11
ALPHA AR667	ASTM 4012	IARM 35E	IARM 35K	LECO 501-675	NIST 16F	NIST 361	NIST 368	VHG 88387-12
ALPHA AR670	BS CSN2-2	IARM 35F	IARM 35KH	LECO 502-016	NIST 1754	NIST 362	NIST 36B	VHG 91231-8
ALPHA AR676	ELTRA 91100-1004	IARM 35G	LECO 501-502	MBH 128X 353C	NIST 1763			

Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity is also determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculate uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S = Standard deviation, t = t-value at 95% CI, and n = number of observations.

$$1. N_{min} = \max(10, \sqrt[3]{N_{prod}})$$

$$2. U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

The International Standards Organization (ISO) definitions, expressed in ISO Guide 30-1992 list the following:

Certifying Body: Any technically competent body (organization or firm, public or private) that issues a reference material certificate with the information detailed in ISO Guide 31. The only generally accepted certifying body in the United States for primary standards or Standard Reference Materials (SRM) is the U. S. Department of Commerce, National Institute of Standards & Technology (NIST), Gaithersburg, MD. All other certifying bodies in the United States produce Reference Materials (RM) or Certified Reference Materials (CRM).

Reference Material (RM): Material or substance, with one or more property values that are sufficiently homogeneous and well established, to be used for the calibration of an apparatus, the assessment of a measurement method, or for assigning values to materials.

Certified Reference Material (CRM): Reference material, accompanied by a certificate, with one or more property values certified by a procedure, which establishes its traceability to an accurate realization of the unit in which the property values are expressed, and for which each certified value is accompanied by an uncertainty at a stated level of confidence.

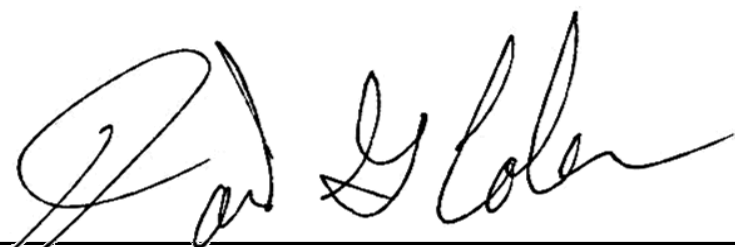
Inter-Laboratory Analysis Program (ILAP): ASTM Standard E691-87 applies to inter-laboratory studies to "Determine the Precision of a Single Test Method", but also outlines a well thought out and logical plan for conducting an inter laboratory program involving multiple analytical techniques. Therefore, the guidelines established in ASTM E691-87 were applied to all aspects of this inter laboratory program, including the protocols for planning, handling, analysis and treatment of resulting data.

Methods of Analysis: The "Inter Laboratory Analysis Program" analyzes a wide variety of materials, and as a result, no single analytical method would provide optimum analytical results. Therefore, a combination of ASTM Standard Methods for classical wet chemistry, ICP, AA, Optical Emission, X-Ray spectrometric, and other accepted methods were used to produce analytical data. Carbon, Sulfur, Nitrogen, and Oxygen results were supplied from combustion and OE instrument procedures.

Expiration of Certification: The certification of this IARM is valid indefinitely, within the uncertainty specified, provided the IARM is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the IARM is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Instructions for Use: The test surface is on the side opposite to the labeled surface, which includes the IARM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. **Chips are not to be used for Oxygen analysis.**

Selection of Materials: A "batch" or "series" is defined as a continuous length of bar produced from a single heat. The majority of IARM materials are in wrought condition; other methods of manufacture are utilized if necessary. ILAP samples are removed from equal sections from the total length of the bar. A portion of each section is converted to chips and a thin (pin) disk for analysis by classical wet chemistry, ICP, AA, and combustion procedures, and the balance remains as a thick disk for OES and X-Ray analysis.



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